

<b>Notice of References Cited</b>	Application/Control No. 10/786,622	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner Mei Q. Huang	Art Unit 1713	Page 1 of 1

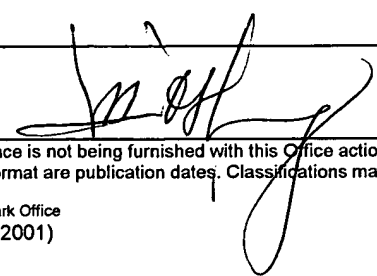
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**NON-PATENT DOCUMENTS**

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